Applicant(s)/Patent Under Application/Control No. Reexamination 10/050,603 TANAKA, YOJI Notice of References Cited Examiner Art Unit Page 1 of 1 1722 Emmanuel S. Luk **U.S. PATENT DOCUMENTS** Date Document Number Classification Name Country Code-Number-Kind Code MM-YYYY 04-1970 425/553 Α US-3508299 Ahern US-4370119 425/352 Watanabe В 01-1983 425/553 US-5439371 08-1995 Sawaya C D US-5472335 12-1995 Morikita 425/556 US-5658600 08-1997 Okada et al 425/192 R Ε US-F G US-US-Н US-1 J US-US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν О Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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